		Application/Control No.	Applicant(s)/Pe	Applicant(s)/Patent under Reexamination	on
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		Examiner	Art Unit		
		Nguyen, Huy D	2617		
	ORIGINAL		INTERNATIONAL CLASSIFICATION	CLASSIFICATIO	z
CLASS		SUBCLASS	CLAIMED	NON-CLAIMED	AIMED
455	453		Н 0 4 0 7 /20		
	CROSS REFERENCE(S)	E(S)			
CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)	CLASS PER BLOCK)			
455 512	2 435.3				
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(Legal Instruments Examiner) (Date)		SUPERMISORY PATENT EXAMINER (Primary Examiner)	ER (25/06 (bate)	O.G. Print Claim(s)	O.G. Print Figure 3

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